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# 1 [Management information systems curricula in the United States and the Republic of China: a comparative study](#)



Betty W. Hwang, Andrew B. Whinston, Wilhelmina Savenye

 March 1992 **ACM SIGCSE Bulletin**, **Proceedings of the twenty-third SIGCSE technical symposium on Computer science education**, Volume 24 Issue 1
Full text available: [pdf \(1.01 MB\)](#)Additional Information: [full citation](#), [abstract](#), [references](#), [index terms](#)

The purpose of this study was to investigate and compare the Management Information Systems (MIS) curricula in higher education in the United States (U.S.) and the Republic of China (R.O.C.). Several factors that affect the MIS curricula and its development in these two countries were closely examined. Similarities and differences were identified and compared; strengths and weaknesses were analyzed and described. In particular, this study focused on the undergraduate MIS programs ...

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Relevance scale ☐ ☐ ☐ ☐ ☐**1 [Auto-summarization of audio-video presentations](#)**

Liwei He, Elizabeth Sanocki, Anoop Gupta, Jonathan Grudin

October 1999 **Proceedings of the seventh ACM international conference on Multimedia (Part 1)**Full text available:  pdf(1.55 MB)Additional Information: [full citation](#), [abstract](#), [references](#), [citations](#), [index terms](#)

As streaming audio-video technology becomes widespread, there is a dramatic increase in the amount of multimedia content available on the net. Users face a new challenge: How to examine large amounts of multimedia content quickly. One technique that can enable quick overview of multimedia is video summaries; that is, a shorter version assembled by picking important segments from the original. We evaluate three techniques for automatic creation of summaries for online audio-video ...

**Keywords:** corporate training, digital library, streaming media, user evaluation, user log analysis, video on-demand, video summarization

**2 [Using offline documentation online](#)**

Lynne A. Price

May 1981 **ACM SIGSOC Bulletin , Proceedings of the joint conference on Easier and more productive use of computer systems. (Part - II): Human interface and the user interface - Volume 1981, Volume 13 Issue 2-3**Full text available:  pdf(495.82 KB)Additional Information: [full citation](#), [abstract](#), [references](#), [citations](#), [index terms](#)


Current interactive programs usually provide some form of online documentation in addition to the traditional hard-copy user's manual. To save the expense of writing two documents covering the same material, it is not uncommon to find offline manuals that are available interactively as well as printed versions of material originally organized for online use. Because of the difficulties inherent in using the same material in different ways, neither approach is totally satisfactory. The THUMB ...

**Keywords:** Documentation, Online assistance, Text structure, User interface, Word processing

**3 [Learning subjective relevance to facilitate information access](#)**

James R. Chen, Nathalie Mathé

December 1995 **Proceedings of the fourth international conference on Information and knowledge management**

Full text available:  [pdf\(943.28 KB\)](#) Additional Information: [full citation](#), [references](#), [index terms](#)

4 Management information systems curricula in the United States and the Republic of China: a comparative study



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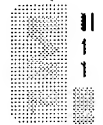
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